

Substitute for form 1449A/PTO

## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet

of 1

Complete if Known	
<b>Application Number</b>	10/695,475
<b>Filing Date</b>	Concurrently Herewith
<b>First Named Inventor</b>	Hsu et al.
<b>Group Art Unit</b>	Not Yet Assigned
<b>Examiner Name</b>	Not Yet Assigned
<b>Attorney Docket Number</b>	ARC920030067LS1

## U.S. PATENT DOCUMENTS

## U.S. PATENT PUBLICATIONS

U.S. PATENT PUBLIC						
Examiner Initials*	Cite No.	U.S. Patent Document Number	Kind Code* (if known)	Name of Patentee or Applicant/Inventor of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner initials*	Cite No.*	Include name of the author (in CAPITAL LETTERS), title of article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
		P. M. Chen et al., "RAID: High-Performance, Reliable Secondary Storage," <i>ACM Computing Surveys</i> , 26, 2, pp. 145-185, June 1994.	
		J. Menon et al., "A Comparison of Sparing Alternatives For Disk Arrays," <i>Proceedings of the 19th Annual International Symposium on Computer Architecture</i> , pp. 318-329, 1992.	
		W. W. Hsu et al., "Characteristics of I/O Traffic in Personal Computer and Server Workloads," <i>IBM Systems Journal</i> , 42, 2, 2003.	
		M. Blaum et al., "The EVENODD code and its generalization: An Efficient Scheme for Tolerating Multiple Disk Failures in RAID Architectures," <i>High Performance Mass Storage and Parallel I/O: Technologies and Applications</i> , Ch. 14, pp. 187-208, 2001.	
		L. Xu et al., "X-Code: MDS Array Codes With Optimal Encoding," <i>IEEE Transactions on Information Theory</i> , 45, 1, pp. 272-276, 1999.	
		G. F. Hughes et al., "Improved Disk-Drive Failure Warnings," <i>IEEE Transactions on Reliability</i> , Vol. 51, No. 3, Sep 2002.	

Examiner Signature		Date Considered	
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\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup> Unique citation designation number. <sup>2</sup> See attached *Kinds of U.S. Patent Documents*. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbol as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a checkmark here if English/Japanese Translation is attached.